Invited Talk

Accelerating Yield Ramp through Real-Time Testing

Sanjiv Taneja, Vice President and General Manager of Test Technology, Cadence

Abstract:
With the increasing need for design specific yield optimization in nanometer technologies, it is becoming increasingly important to accelerate the identification of the root cause of systematic defects under very tight test cost constraints. This talk will give a high level overview of addressing these demanding challenges through a mix of cross-disciplinary EDA technologies spanning scan diagnostics, DFT, ATPG, BIST, DFM and real-time monitoring from ATE systems.